Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/785,445	WANG ET AL.
Examiner	Art Unit
Matthew D. Matzek	1771

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Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED					
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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INVENTOR / ASSIGNES	11/30/15	אניע		
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